

# 74F827, 74F828

10-Bit Buffers/Line Drivers

The 74827 and 74828 10-bit bus buffers provide high performance bus interface buffering for wide data/address paths or buses carrying parity. The 10-bit buffers have NOR output enables for maximum control flexibility. The 74F828 is an inverting version of the 74F827.

# Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

# **Quality Overview**

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
  - Class Q Military
  - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
  - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

April 1988 Revised February 2004 74F827 • 74F828 10-Bit Buffers/Line Drivers

# FAIRCHILD

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# 74F827 • 74F828 10-Bit Buffers/Line Drivers

### **General Description**

The 74F827 and 74F828 10-bit bus buffers provide high performance bus interface buffering for wide data/address paths or buses carrying parity. The 10-bit buffers have NOR output enables for maximum control flexibility. The 74F828 is an inverting version of the 74F827.

# **Ordering Code:**

Order Number	Package Number	Package Description				
74F827SC (Note 1)	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide				
74F827SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide				
74F828SC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide				
74F828SPC (Note 1)	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide				

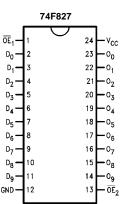
**Features** 

■ 3-STATE output

■ 74F828 is inverting

Note 1: Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

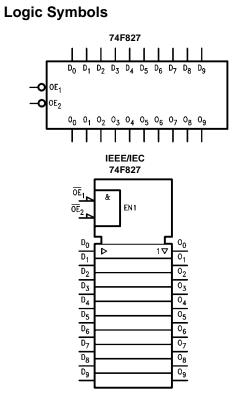
# **Connection Diagrams**

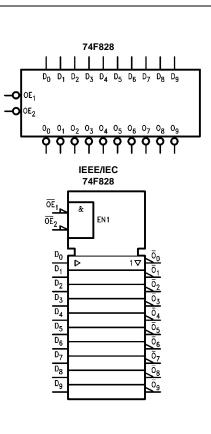




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# **Unit Loading/Fan Out**

Pin Names	Description	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>		
Fin Names	Description	HIGH/LOW	Output I <sub>OH</sub> /I <sub>OL</sub>		
$\overline{OE}_1, \overline{OE}_2$	Output Enable Input	1.0/1.0	20 μA/–0.6 mA		
D <sub>0</sub> -D <sub>7</sub>	Data Inputs	1.0/1.0	20 μA/–0.6 mA		
O <sub>0</sub> O <sub>7</sub>	Data Outputs, 3-STATE	600/106.6 (80)	-12 mA/64 mA (48 mA)		

## **Functional Description**

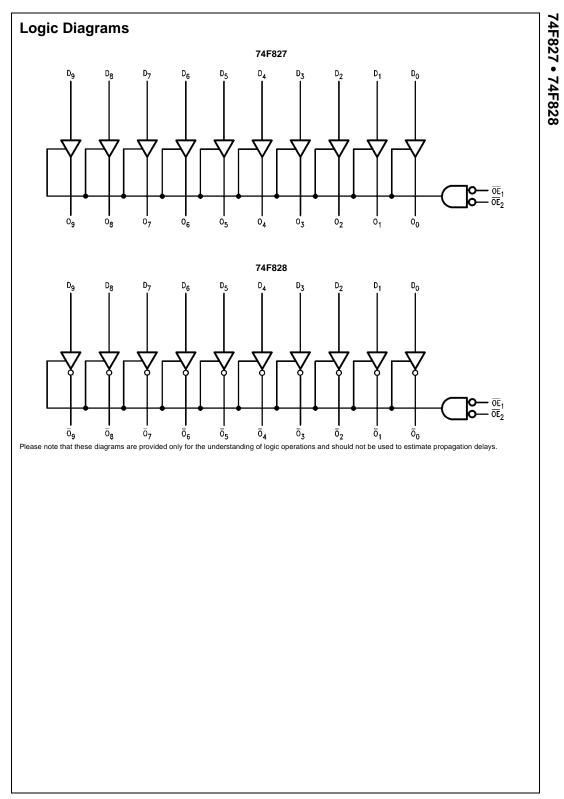
The 74F827 and 74F828 are line drivers designed to be employed as memory address drivers, clock drivers and bus-oriented transmitters/receivers which provide improved PC board density. The devices have 3-STATE outputs controlled by the Output Enable  $(\overline{OE})$  pins. The outputs can sink 64 mA and source 15 mA. Input clamp diodes limit high-speed termination effects.

## **Function Table**

Inputs		Out	puts	
OE	D <sub>n</sub>	O <sub>n</sub>		Function
		74F827	74F828	
L	Н	Н	L	Transparent
L	L	L	Н	Transparent
н	Х	Z	Z	High Z

H = HIGH Voltage level L = LOW Voltage Level

Z = High Impedance X = Immaterial



## Absolute Maximum Ratings(Note 2)

	-
Storage Temperature	$-65^{\circ}C$ to $+150^{\circ}C$
Ambient Temperature under Bias	$-55^{\circ}C$ to $+125^{\circ}C$
Junction Temperature under Bias	$-55^{\circ}C$ to $+150^{\circ}C$
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 3)	-0.5V to +7.0V
Input Current (Note 3)	-30 mA to +5.0 mA
Voltage Applied to Output	
in HIGH State (with $V_{CC} = 0V$ )	
Standard Output	-0.5V to V <sub>CC</sub>
3-STATE Output	-0.5V to +5.5V
Current Applied to Output	
in LOW State (Max)	twice the rated $I_{OL}$ (mA)

## **Recommended Operating Conditions**

Free Air Ambient	Temperature
Supply Voltage	

0°C to +70°C +4.5V to +5.5V

Note 2: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

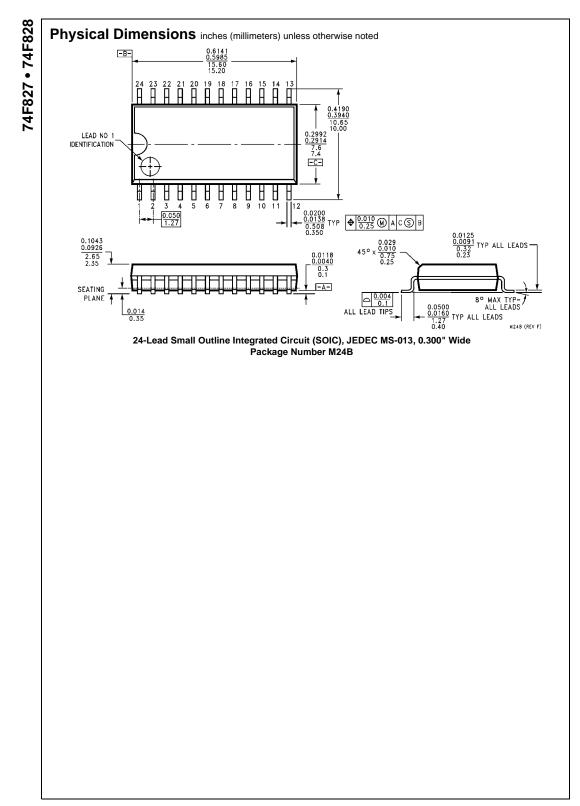
Note 3: Either voltage limit or current limit is sufficient to protect inputs.

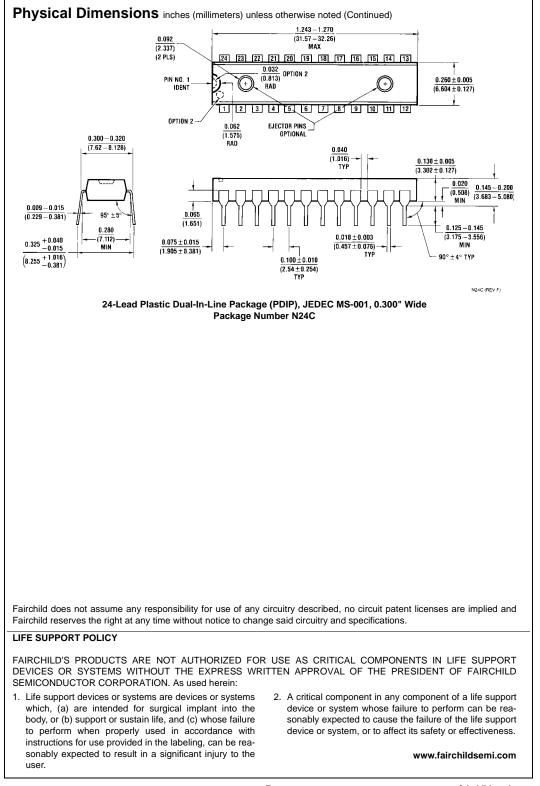
## **DC Electrical Characteristics**

Parameter Min Vcc Conditions Symbol Max Units Тур Input HIGH Voltage 2.0 ٧ Recognized as a HIGH Signal VIH Input LOW Voltage 0.8 V Recognized as a LOW Signal VIL V<sub>CD</sub> Input Clamp Diode Voltage -1.2 V Min  $I_{IN} = -18 \text{ mA}$ I<sub>OH</sub> = -3 mA 24 Output HIGH 10% V<sub>CC</sub> VOH 10% V<sub>CC</sub> V I<sub>OH</sub> = -15 mA Voltage 2.0 Min 5% V<sub>CC</sub> I<sub>OH</sub> = -3 mA 2.7 VOL Output LOW Voltage 10% V<sub>CC</sub> 0.55 V Min  $I_{OL} = 64 \text{ mA}$  $I_{\rm H}$ Input HIGH 5.0  $V_{IN} = 2.7V$ μΑ Max Current Input HIGH Current I<sub>BVI</sub> 7.0 μA Max V<sub>IN</sub> = 7.0V Breakdown Test Output HIGH ICEX 50 μΑ Max  $V_{OUT} = V_{CC}$ Leakage Current  $V_{ID}$ Input Leakage  $I_{ID} = 1.9 \ \mu A$ 4.75 V 0.0 All Other Pins Grounded Test Output Leakage V<sub>IOD</sub> = 150 mV IOD 3.75 μΑ 0.0 Circuit Current All Other Pins Grounded  $\mathsf{I}_{\mathsf{IL}}$ Input LOW Current -0.6 mΑ Max  $V_{IN} = 0.5V$ Max  $V_{OUT} = 2.7V$ Output Leakage Current 50 I<sub>OZH</sub> μA Output Leakage Current Max  $V_{OUT} = 0.5V$ -50 I<sub>OZL</sub> μΑ I<sub>OS</sub> Output Short-Circuit Current -100 -225 mΑ Max  $V_{OUT} = 0V$  $I_{ZZ}$ Bus Drainage Test 500 μΑ 0.0V V<sub>OUT</sub> = 5.25V Power Supply Current (74F827)  $V_0 = HIGH$ ICCH 30 45 mΑ Max  $\overline{V_0} = LOW$ Power Supply Current (74F827) 60 90 mΑ Max ICCL V<sub>O</sub> = HIGH Z Power Supply Current (74F827) 40 60 mΑ Max I<sub>CCZ</sub>  $V_0 = HIGH$ Power Supply Current (74F828) 14 20 I<sub>CCH</sub> mΑ Max ICCL Power Supply Current (74F828) 56 85 mΑ Max  $V_{O} = LOW$ V<sub>O</sub> = HIGH Z Power Supply Current (74F828) 35 50 Max I<sub>CCZ</sub> mΑ

Symbol	Parameter	T <sub>A</sub> = +25°C V <sub>CC</sub> = +5.0V C <sub>L</sub> = 50 pF			$T_{A} = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$		$T_{A} = 0^{\circ}C \text{ to } +70^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	Min	Max	t
t <sub>PLH</sub>	Propagation Delay	1.0	3.0	5.5	1.0	7.5	1.0	6.5	ns
t <sub>PHL</sub>	Data to Output (74F827)	1.5	3.3	5.5	1.5	7.0	1.5	6.0	
t <sub>PLH</sub>	Propagation Delay	1.0	3.0	5.0			1.0	5.5	ns
t <sub>PHL</sub>	Data to Output (74F828)	1.0	2.0	4.0			1.0	4.0	
t <sub>PZH</sub>	Output Enable Time	3.0	5.7	9.0	2.5	10.0	2.5	9.5	ns
t <sub>PZL</sub>	OE to O <sub>n</sub>	3.5	6.8	11.5	3.0	12.5	3.0	12.0	
t <sub>PHZ</sub>	Output Disable Time	1.5	3.3	8.0	1.5	9.0	1.5	8.5	ns
t <sub>PLZ</sub>	OE to On	1.0	3.5	8.0	1.0	9.0	1.0	8.5	

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